

Enhancement Mode Single N-Channel Power MOSFET

SOP8/NMOS/30V/ \pm 20V/1.6V/18A/4.7m Ω

Rev1.1





30V, 4.7mΩ, 18A, Single N-Channel

1.Features

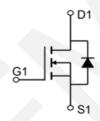
- ◆ 30V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±20V

2.A	ppli	cati	ons

- ♦ Power Switching Application
- Load Switching







Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.	
WP4430K	4430K	SOP8	4,000	48,000	

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V _{DSS}	30	V
Gate to Source Voltage	V_{GSS}	±20	V
Drain Current (DC)	ID	18	А
Drain Current (Pulse), PW≤300μs	I _{DP}	48	А
Total Dissipation	P _D	3	W
Avalanche Energy, Single Pulsed	Eas	86	mJ
Junction Temperature	Tj	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Junction to Ambient	Reja	31	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

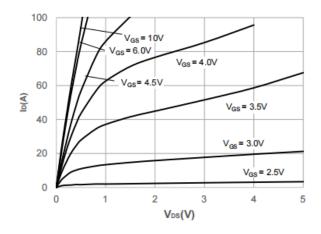
6.Electrical Characteristics at Ta=25°C (Note 3)

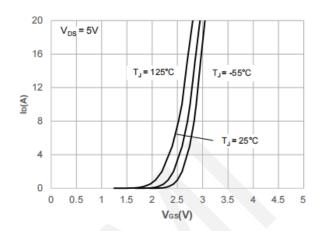
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A$, $V_{GS} = 0 V$	30	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} = 30V, V _{GS} = 0V	-	-	1.0	μΑ
Gate to Source Leakage Current	Igss	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA
Gate Threshold Voltage	$V_{\text{GS(th)}}$	V _{DS} =V _{GS} , I _{DS} =250µA	1.0	1.6	2.5	V
Static Drain to Source On-State	Б	I _D = 12A, V _{GS} = 10V	1	4.7	6.0	mΩ
Resistance	R _{DS(on)}	I _D = 10A, V _{GS} = 4.5V	1	6.5	10	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,	-	1790	-	pF
Output Capacitance	Coss	V _{DS} =15V,	-	225	-	pF
Reverse Transfer Capacitance	Crss	Frequency=1.0MHz	1	180	-	pF
Turn-ON Delay Time	t _{d(on)}		ı	7	-	ns
Rise Time	tr	V _{DD} = 15V, I _{DS} = 9A,	-	15	-	ns
Turn-OFF Delay Time	$t_{\sf d(off)}$	$V_{GS} = 10V$, $R_G = 3\Omega$	-	34	-	ns
Fall Time	t _f		ı	10	-	ns
	Qg	V _{DS} = 15V,	-	34	-	nC
Total Gate Charge	Qgs	$V_{GS} = 0$ to 10V,	1	6.5	-	nC
	Q_{gd}	I _{DS} = 12A	-	7.5	-	nC
Diode Forward Voltage	V _{FSD}	I _S = 12A, V _{GS} = 0V	-	0.85	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

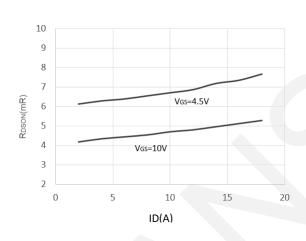


7. Typical electrical and thermal characteristics

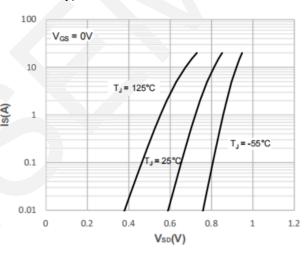




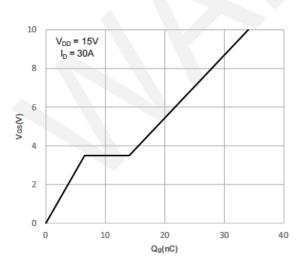
Output Characteristics



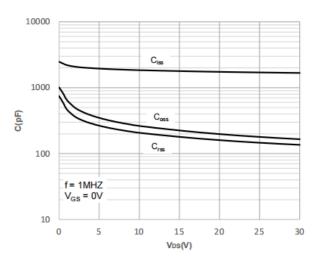
Typical Transfer Characteristics



On-resistance vs. Drain Current



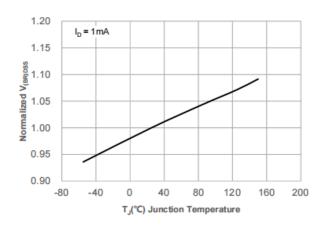
Body Diode Characteristics



Gate Charge Characteristics

Capacitance Characteristics





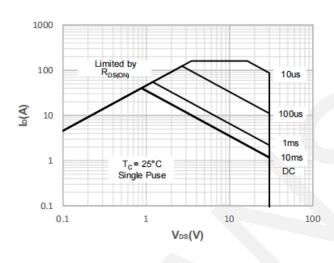
2.2 V_{GS}= 10V I_D = 30A 2 1.8 Normalized Rosgon 1.6 1.4 1.2 1 0.8 0.6 0.4 -80 -40 40 120 160 200 T_J(°C) Junction Temperature

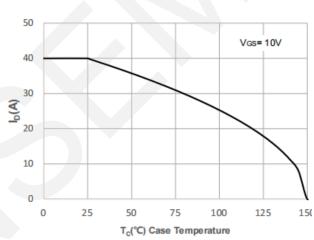
Normalized Breakdown Voltage vs.

Junction Temperature

Normalized on Resistance vs.

Junction Temperature

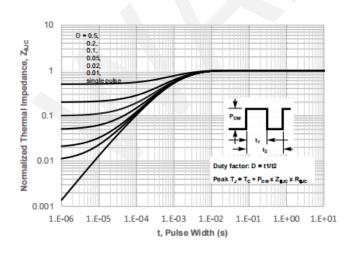


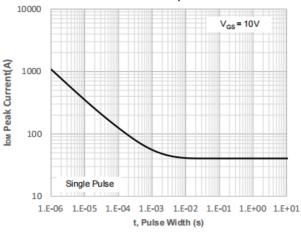


Maximum Safe Operating Area

Maximum Continuous Drain Current vs.

Case Temperature



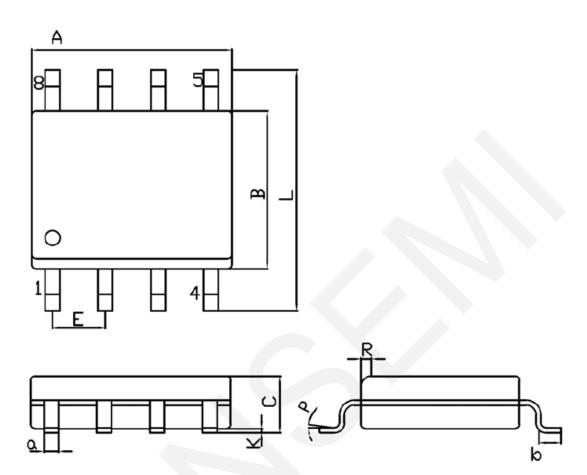


Normalized Maximum Transient Thermal Impedance

Peak Current Capacity



8.Package Dimensions



Symbol	Symbol Dimensions In Millimeters		Symbol	Dimensions I	n Millimeters
Symbol	Min	Max	Symbol	Min	Max
A	4.70	5,10	С	1,35	1,75
В	3.70	4,10	۵	0,35	0.49
L	5.80	6,20	R	0'30	0.60
E	1.27BSC		Р	0+	7*
K	0.12	0.22	b	0.40	1,25



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